Feature	Technical Explanation	Benefits
New APG Functions	· Clustertest	Automatically higher test coverage
	Generation of VB. NET-Code	 Free choice of programming language
	Adjustable text length	Avoidance of long texts
	Better version handling	 Weighting according to component relevance
		 Avoid redundant tests by combining identical tests
DebugRobot (optional)	Fully automated debugging	Automatic debugging, fully automated
	Transistor testing made easy	 The potential for errors is reduced
	Diodes can be learned automatically	Saving costs and time
		Faster time to market for new products (NPI)
Adjusting Layout Display	· Communication with Kernel \rightarrow layout selectable	Avoiding error messages due to non-conforming error texts
Retest Failing Components	Simple and reliable repetition of failed tests	Significant time savings with board retests
Free Access To Test Results	Extended callback functions for dynamic collection	Freely configurable test program information transfer without file
	of test data	transfer or direct creation of your own file format
Visual Basic Support	Support for all current VB versions	Free choice of existing company licenses
Test Programm Batch Translator	Automatically translate & release all existing test programms	 Serious time savings with CITE updates
FailSim Advantages	Simplified operation when debugging	Save time during debugging
	Larger test scope	Verification of further test methods (e.g.parallel combinations)
USM-Module & AMU-SPS Port CITE Integration	Corresponding kernel commands implemented	· Simple programming without low level procedures
Extension Of Test Log File	All relevant test parameters in the XML log file	Standardized XML format
		Compatible expandable at any time
		 Access to all test information for any evaluations
CITE With Reduced User Rights (optional)	Secure, concealed access to Windows admin rights	Manage User Rights easily
Standardized Remote Control App	Remote control of CITE from superior instance	Clearly stuctured processes such as Process locking
		Realization of Industry 4.0 algorithms